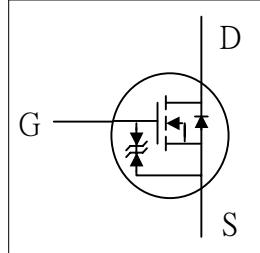
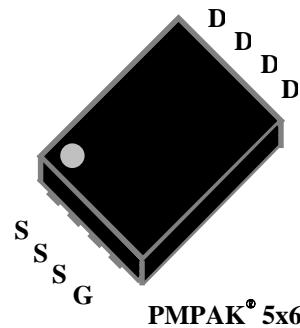




- ▼ Simple Drive Requirement
- ▼ SO-8 Compatible with Heatsink
- ▼ Low On-resistance
- ▼ RoHS Compliant & Halogen-Free



$BV_{DSS}$	30V
$R_{DS(ON)}$	4.5mΩ
$I_D^4$	60A



## Description

XP4024 series are innovative design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The PMPAK® 5x6 package is special for DC-DC converters application and the foot print is compatible with SO-8 with backside heat sink and lower profile.

## Absolute Maximum Ratings@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	30	V
$V_{GS}$	Gate-Source Voltage	+20	V
$I_D @ T_C=25^\circ\text{C}$	Drain Current (Chip), $V_{GS} @ 10\text{V}^4$	60	A
$I_D @ T_A=25^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}^3$	26.1	A
$I_D @ T_A=70^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}^3$	20.9	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	160	A
$P_D @ T_C=25^\circ\text{C}$	Total Power Dissipation	36.7	W
$P_D @ T_A=25^\circ\text{C}$	Total Power Dissipation <sup>3</sup>	5	W
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Value	Unit
$R_{thj-c}$	Maximum Thermal Resistance, Junction-case	3.4	°C/W
$R_{thj-a}$	Maximum Thermal Resistance, Junction-ambient <sup>3</sup>	25	°C/W

**Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$ , $I_{\text{D}}=250\mu\text{A}$	30	-	-	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=10\text{V}$ , $I_{\text{D}}=20\text{A}$	-	3.5	4.5	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$ , $I_{\text{D}}=20\text{A}$	-	5	8.5	$\text{m}\Omega$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$ , $I_{\text{D}}=250\mu\text{A}$	1.2	1.6	2.5	V
$g_{\text{fs}}$	Forward Transconductance	$V_{\text{DS}}=10\text{V}$ , $I_{\text{D}}=20\text{A}$	-	70	-	S
$I_{\text{DSS}}$	Drain-Source Leakage Current	$V_{\text{DS}}=24\text{V}$ , $V_{\text{GS}}=0\text{V}$	-	-	10	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}$ , $V_{\text{DS}}=0\text{V}$	-	-	$\pm 30$	$\mu\text{A}$
$Q_g$	Total Gate Charge	$I_{\text{D}}=20\text{A}$	-	15	24	nC
$Q_{\text{gs}}$	Gate-Source Charge		-	4	-	nC
$Q_{\text{gd}}$	Gate-Drain ("Miller") Charge		-	8	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time	$V_{\text{DS}}=15\text{V}$	-	14	-	ns
$t_r$	Rise Time		-	10	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time		-	33	-	ns
$t_f$	Fall Time		-	18	-	ns
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	1500	2400	pF
$C_{\text{oss}}$	Output Capacitance		-	320	-	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance		-	210	-	pF
$R_g$	Gate Resistance	$f=1.0\text{MHz}$	-	1.2	2.4	$\Omega$

**Source-Drain Diode**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_{\text{SD}}$	Forward On Voltage <sup>2</sup>	$I_{\text{S}}=20\text{A}$ , $V_{\text{GS}}=0\text{V}$	-	-	1.2	V
$t_{\text{rr}}$	Reverse Recovery Time	$I_{\text{S}}=20\text{A}$ , $V_{\text{GS}}=0\text{V}$ , $dI/dt=100\text{A}/\mu\text{s}$	-	20	-	ns
$Q_{\text{rr}}$	Reverse Recovery Charge		-	5	-	nC

**Notes:**

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board,  $t \leq 10\text{sec}$ ; 60°C/W at steady state.
- 4.Package limitation current is 60A .

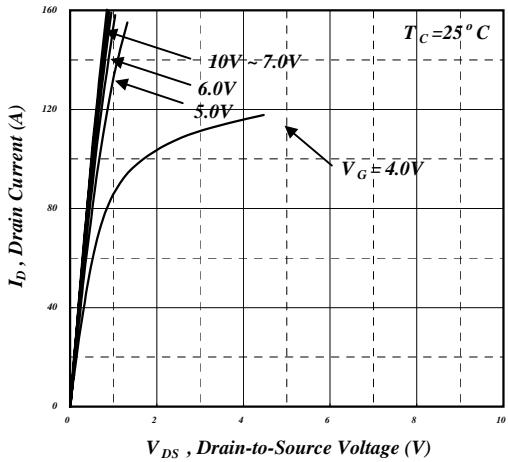
THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

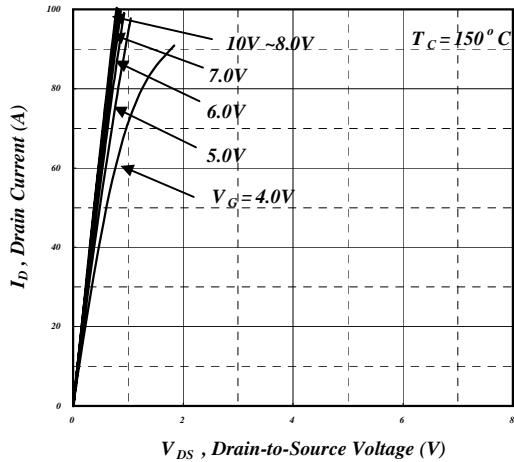
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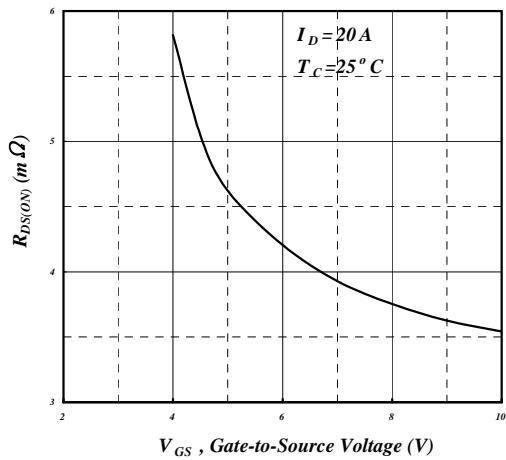
XSEMI RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN.



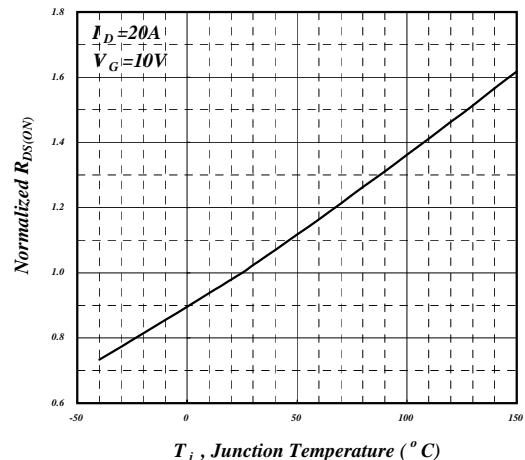
**Fig 1. Typical Output Characteristics**



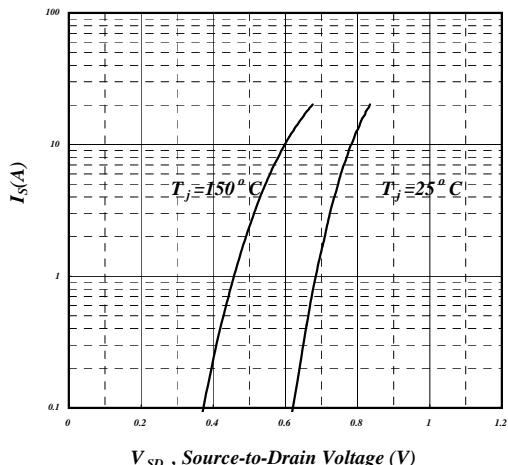
**Fig 2. Typical Output Characteristics**



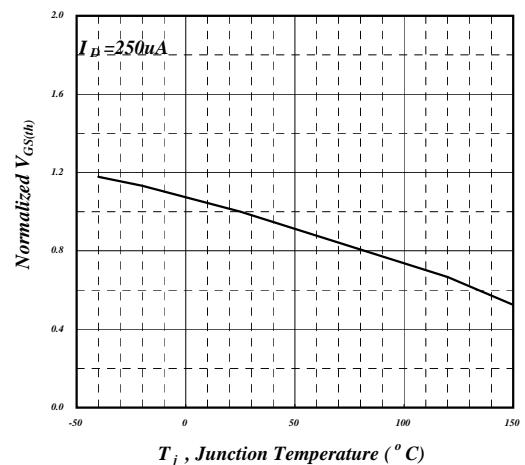
**Fig 3. On-Resistance v.s. Gate Voltage**



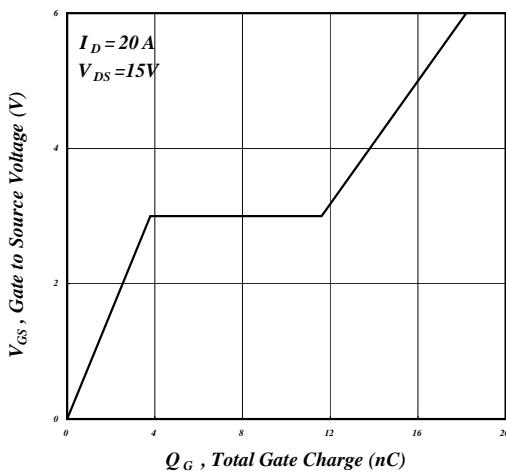
**Fig 4. Normalized On-Resistance v.s. Junction Temperature**



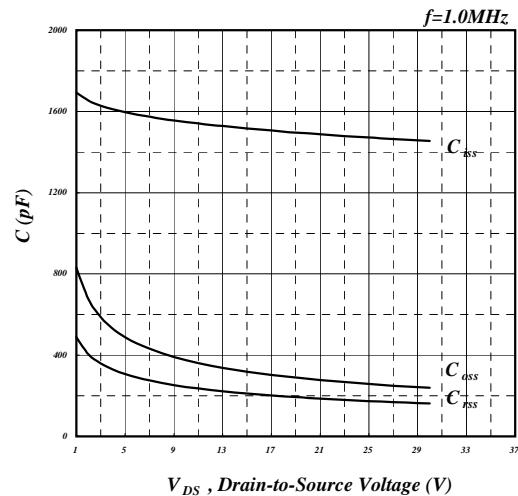
**Fig 5. Forward Characteristic of Reverse Diode**



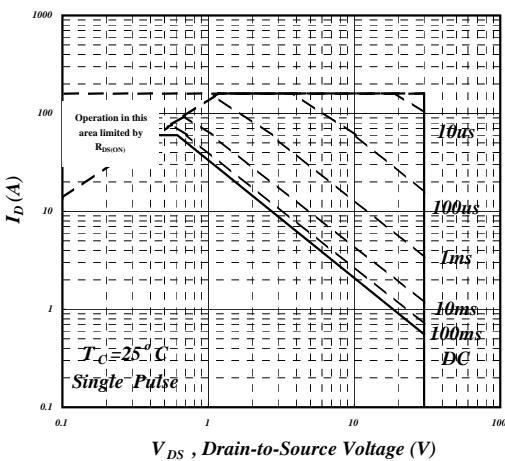
**Fig 6. Gate Threshold Voltage v.s. Junction Temperature**



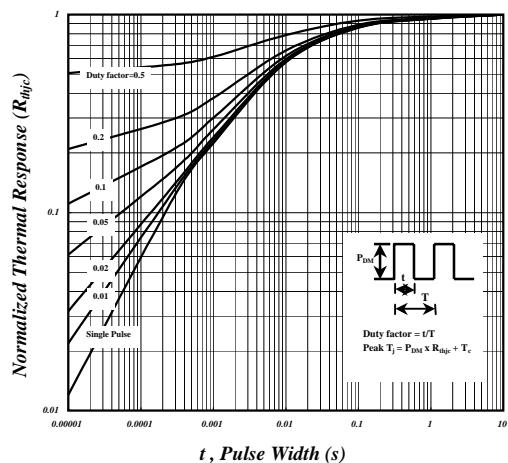
**Fig 7. Gate Charge Characteristics**



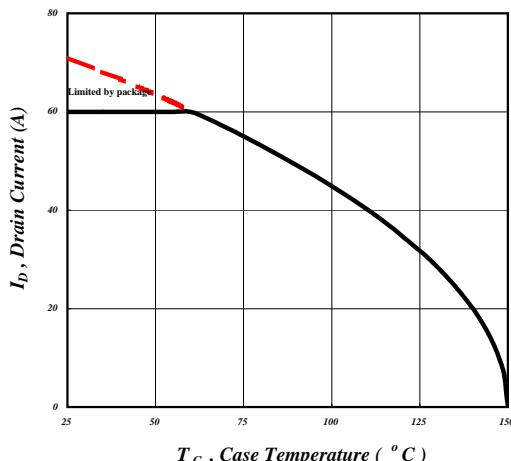
**Fig 8. Typical Capacitance Characteristics**



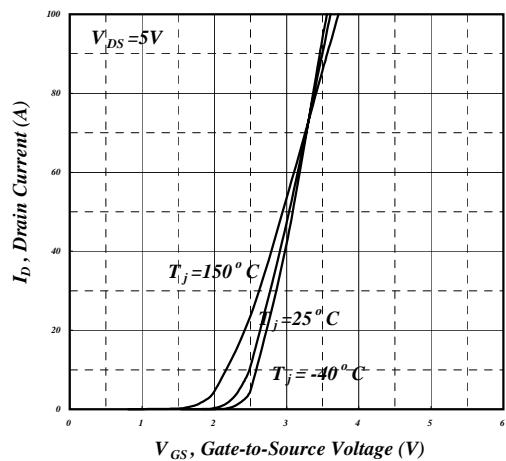
**Fig 9. Maximum Safe Operating Area**



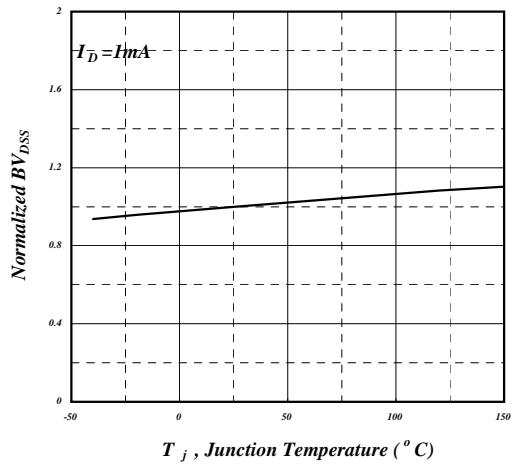
**Fig 10. Effective Transient Thermal Impedance**



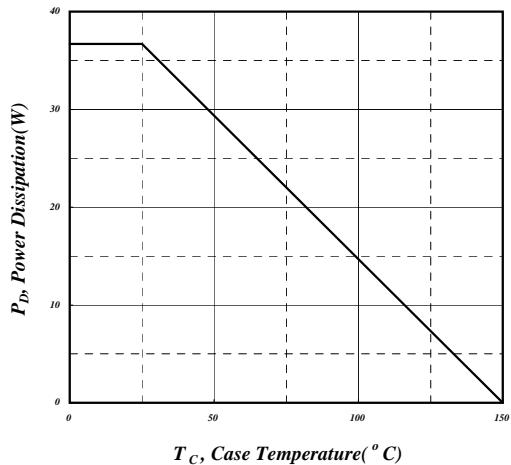
**Fig 11. Drain Current v.s. Case Temperature**



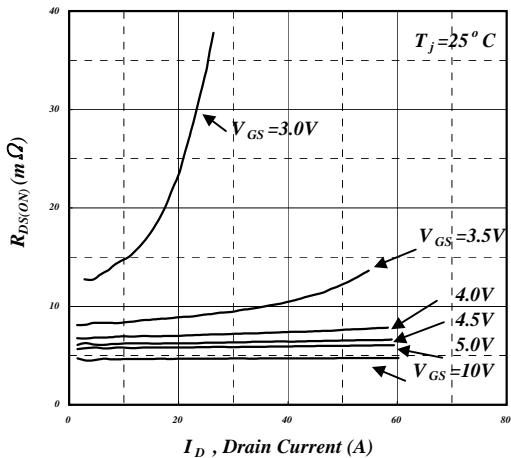
**Fig 12. Transfer Characteristics**



**Fig 13. Normalized  $BV_{DSS}$  v.s. Junction**



**Fig 14. Total Power Dissipation**



**Fig 15. Typ. Drain-Source on State Resistance**